SN74CBT1G125 SINGLE FET BUS SWITCH

SCDS046C - FEBRUARY 1998 - REVISED OCTOBER 1998

- **5-**Ω Switch Connection Between Two Ports
- TTL-Compatible Control Input Levels
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Packaged in Plastic Small-Outline Transistor (DBV, DCK) Packages

description

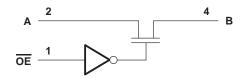
The SN74CBT1G125 features a single high-speed line switch. The switch is disabled when the output-enable (\overline{OE}) input is high.

The SN74CBT1G125 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE				
INPUT OE	FUNCTION			
L	A port = B port			
Н	Disconnect			

FUNCTION TABLE

logic diagram (positive logic)



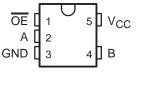


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DBV OR DCK PACKAGE

(TOP VIEW)

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC} Input voltage range, V _I (see Note 1)	
Continuous channel current	
Input clamp current, I_{IK} ($V_{I/O} < 0$)	
Package thermal impedance, θ_{IA} (see Note 2): DBV package	
Storage temperature range, T _{stg}	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 3)

		MIN	MAX	UNIT
Vcc	Supply voltage	4	5.5	V
VIH	High-level control input voltage	2		V
VIL	Low-level control input voltage		0.8	V
Т _А	Operating free-air temperature	-40	85	°C

NOTE 3: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER			TEST CONDITIONS			MIN	TYP‡	MAX	UNIT
VIK		V _{CC} = 4.5 V,	Ij = -18 mA					-1.2	V
Ц		V _{CC} = 5.5 V,	$V_I = 5.5 V \text{ or GND}$					±1	μΑ
Icc		V _{CC} = 5.5 V,	I _O = 0,	$V_{I} = V_{CC} \text{ or } GN$	ND			1	μA
Ci	Control input	V _I = 3 V or 0					3		pF
C _{io(OI}	FF)	V _O = 3 V or 0,	$OE = V_{CC}$				4		pF
r _{on} §		$V_{CC} = 4 V,$	TYP at V _{CC} = 4 V,	VI = 2.4 V,	lj = 15 mA		14	20	
		V. 0	$V_1 = 0$	I _I = 64 mA			5	7	Ω
		$V_{CC} = 4.5 V$	VI=0	I _I = 30 mA			5	7	52
			V _I = 2.4 V,	lj = 15 mA			10	15	

[‡] All typical values are at V_{CC} = 5 V (unless otherwise noted), T_A = 25°C.

§ Measured by the voltage drop between the A and the B terminals at the indicated current through the switch. On-state resistance is determined by the lower of the voltages of the two (A or B) terminals.

switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

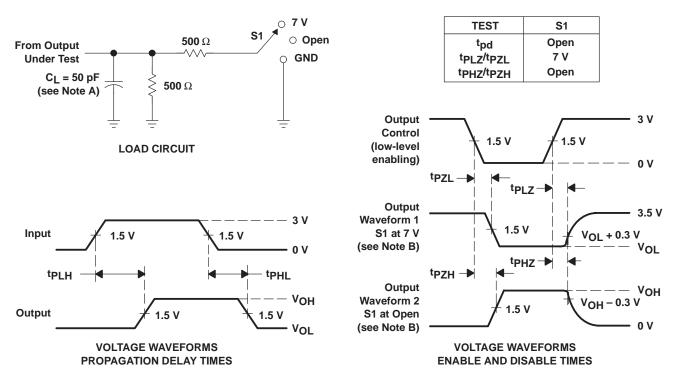
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 4 V	V _{CC} = 5 V ± 0.5 V		UNIT
			MIN MAX	MIN	MAX	
t _{pd} ¶	A or B	B or A	0.35		0.25	ns
ten	OE	A or B	5.5	1.6	4.9	ns
^t dis	OE	A or B	4.5	1	4.2	ns

The propagation delay is the calculated RC time constant of the typical on-state resistance of the switch and the specified load capacitance, when driven by an ideal voltage source (zero output impedance).



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PARAMETER MEASUREMENT INFORMATION

- NOTES: A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f \leq 2.5 ns, t_f \leq 2.5 ns.
 - D. The output is measured with one input transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. tPLH and tPHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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